

<b>Notice of References Cited</b>	Application/Control No. 10/606,768	Applicant(s)/Patent Under Reexamination HA ET AL.	
	Examiner Chuc D. Tran	Art Unit 2821	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,686,699	02-2004	Yumoto, Akira	315/169.3
*	B	US-6,734,636	05-2004	Sanford et al.	315/169.3
*	C	US-6,806,497	10-2004	Jo, Hiroaki	257/59
*	D	US-6,683,417	01-2004	Lee et al.	315/169.3
*	E	US-6,693,383	02-2004	Bae et al.	315/169.1
*	F	US-2003/0107565	06-2003	Libsch et al.	345/211
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.